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**NTE74C74**  
**Integrated Circuit**  
**TTL- CMOS Dual D-Type Positive Edge**  
**Triggered Flip-Flop with Preset & Clear**  
**14-Lead DIP**

**Description:**

The NTE74C74 dual D-type flip-flop is a monolithic complementary MOS (CMOS) integrated circuit in a 14-Lead DIP type package constructed with N- and P-channel enhancement transistors. Each flip-flop has independent data, preset, clear and clock inputs and Q and  $\overline{Q}$  outputs. The logic level present at the data input is transferred to the output during the positive going transition of the clock pulse. Preset or clear is independent of the clock and accomplished by a low level at the preset or clear.

**Features:**

- Wide Supply Range: 3V to 15V
- Tenth Power TTL Compatible: Drive 2 LPT<sup>2</sup>L Loads
- High Noise Immunity: 0.45 V<sub>CC</sub> (typ)
- Low Power: 50nW (typ)
- Medium Speed Operation: 10Mhz (typ) with 10V Supply

**Applications:**

- Automotive
- Data Terminals
- Instrumentation
- Medical Electronics
- Alarm Systems
- Industrial Electronics
- Remote Metering
- Computers

**Absolute Maximum Ratings:** (Note 1)

Voltage at Any Pin .....	-0.3V to V <sub>CC</sub> +0.3V
Power Dissipation, P <sub>D</sub> .....	700mW
Operating V <sub>CC</sub> Range .....	3V to 15V
Maximum V <sub>CC</sub> Voltage .....	18V
Operating Temperature Range, T <sub>A</sub> .....	-55° to +125°C
Storage Temperature Range, T <sub>stg</sub> .....	-65° to +150°C
Lead Temperature (During Soldering, 10sec), T <sub>L</sub> .....	+260°C

Note 1. "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range", they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

**DC Electrical Characteristics:** ( $T_A = -55^\circ$  to  $+125^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions		Min	Typ	Max	Unit
<b>CMOS to CMOS</b>							
Logical "1" Input Voltage	$V_{IN(1)}$	$V_{CC} = 5\text{V}$		3.5	-	-	V
		$V_{CC} = 10\text{V}$		8.0	-	-	V
Logical "0" Input Voltage	$V_{IN(0)}$	$V_{CC} = 5\text{V}$		-	-	1.5	V
		$V_{CC} = 10\text{V}$		-	-	2.0	V
Logical "1" Output Voltage	$V_{OUT(1)}$	$V_{CC} = 5\text{V}$		4.5	-	-	V
		$V_{CC} = 10\text{V}$		9.0	-	-	V
Logical "0" Output Voltage	$V_{OUT(0)}$	$V_{CC} = 5\text{V}$		-	-	0.5	V
		$V_{CC} = 10\text{V}$		-	-	1.0	V
Logical "1" Input Current	$I_{IN(1)}$	$V_{CC} = 15\text{V}$		-	-	1.0	$\mu\text{A}$
Logical "0" Input Current	$I_{IN(0)}$	$V_{CC} = 15\text{V}$		-1.0	-	-	$\mu\text{A}$
Supply Current	$I_{CC}$	$V_{CC} = 15\text{V}$		-	0.05	60	$\mu\text{A}$
<b>CMOS/LPTTL Interface</b>							
Logical "1" Input Voltage	$V_{IN(1)}$	$V_{CC} = 4.75\text{V}$		$V_{CC}-1.5$	-	-	V
Logical "0" Input Voltage	$V_{IN(0)}$	$V_{CC} = 4.75\text{V}$		-	-	0.8	V
Logical "1" Output Voltage	$V_{OUT(1)}$	$V_{CC} = 4.75\text{V}, I_O = -360\mu\text{A}$		2.4	-	-	V
Logical "0" Output Voltage	$V_{OUT(0)}$	$V_{CC} = 4.75\text{V}, I_O = 360\mu\text{A}$		-	-	0.4	V
<b>Output Drive</b>							
Output Source Current (P-Channel)	$I_{SOURCE}$	$V_{CC} = 5\text{V}$	$V_{IN(0)} = 0, V_{OUT} = 0, T_A = +25^\circ\text{C}$	-1.75	-	-	mA
		$V_{CC} = 10\text{V}$		-8	-	-	mA
Output Sink Current (N-Channel)	$I_{SINK}$	$V_{CC} = 5\text{V}$	$V_{IN(0)} = 0, V_{OUT} = V_{CC}, T_A = +25^\circ\text{C}$	1.75	-	-	mA
		$V_{CC} = 10\text{V}$		8	-	-	mA

**AC Electrical Characteristics:** ( $T_A = +25^\circ$ ,  $C_L = 50\text{pF}$ , Note 2 unless otherwise specified)

Parameter	Symbol	Test Conditions		Min	Typ	Max	Unit
Propagation Delay Time to a Logical "0" $t_{pd0}$ or Logical "1" $t_{pd1}$ from Clock to Q or $\bar{Q}$	$t_{pd}$	$V_{CC} = 5\text{V}$		-	180	300	ns
		$V_{CC} = 10\text{V}$		-	70	110	ns
Propagation Delay Time to a Logical "0" from Preset or Clear	$t_{pd}$	$V_{CC} = 5\text{V}$		-	180	300	ns
		$V_{CC} = 10\text{V}$		-	70	110	ns
Propagation Delay Time to a Logical "1" from Preset or Clear	$t_{pd}$	$V_{CC} = 5\text{V}$		-	250	400	ns
		$V_{CC} = 10\text{V}$		-	100	150	ns
Time Prior to Clock Pulse that Data Must be Present, $t_{SETUP}$	$t_{SO}, t_{S1}$	$V_{CC} = 5\text{V}$		100	50	-	ns
		$V_{CC} = 10\text{V}$		40	20	-	ns
Time after Clock Pulse that Data Must be Held	$t_{H0}, t_{H1}$	$V_{CC} = 5\text{V}$		-	-20	0	ns
		$V_{CC} = 10\text{V}$		-	-8.0	0	ns
Minimum Clock Pulse Width ( $t_{WL} = t_{WH}$ )	$t_{PW1}$	$V_{CC} = 5\text{V}$		-	100	250	ns
		$V_{CC} = 10\text{V}$		-	40	100	ns
Minimum Preset and Clear Pulse Width	$t_{PW2}$	$V_{CC} = 5\text{V}$		-	100	160	ns
		$V_{CC} = 10\text{V}$		-	40	70	ns
Maximum Clock Rise and Fall Time	$t_r, t_f$	$V_{CC} = 5\text{V}$		15	-	-	$\mu\text{s}$
		$V_{CC} = 10\text{V}$		5	-	-	$\mu\text{s}$

Note 2. AC Parameters are guaranteed by DC correlated testing.

**AC Electrical Characteristics (Cont'd):** ( $T_A = +25^\circ$ ,  $C_L = 50\text{pF}$ , Note 2 unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Maximum Clock Frequency	$f_{MAX}$	$V_{CC} = 5\text{V}$	2.0	3.5	–	MHz
		$V_{CC} = 10\text{V}$	5.0	8.0	–	MHz
Input Capacitance	$C_{IN}$	Any Input, Note 3	–	5.0	–	pF
Power Dissipation Capacitance	$C_{PD}$	Note 4	–	40	–	pF

Note 2. AC Parameters are guaranteed by DC correlated testing.

Note 3. Capacitance is guaranteed by periodic testing.

Note 4.  $C_{PD}$  determines the no load AC power consumption of any CMOS device.

**Truth Table:**

Preset	Clear	$Q_n$	$\bar{Q}_n$
0	0	0	0
0	1	1	0
1	0	0	1
1	1	NC	NC

NC = No change in output from previous status

**Pin Connection Diagram**



